

Search Notes

Application/Control No.

10/682,224

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

KIKUCHI ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
updated	previous search	2/7/2006	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR